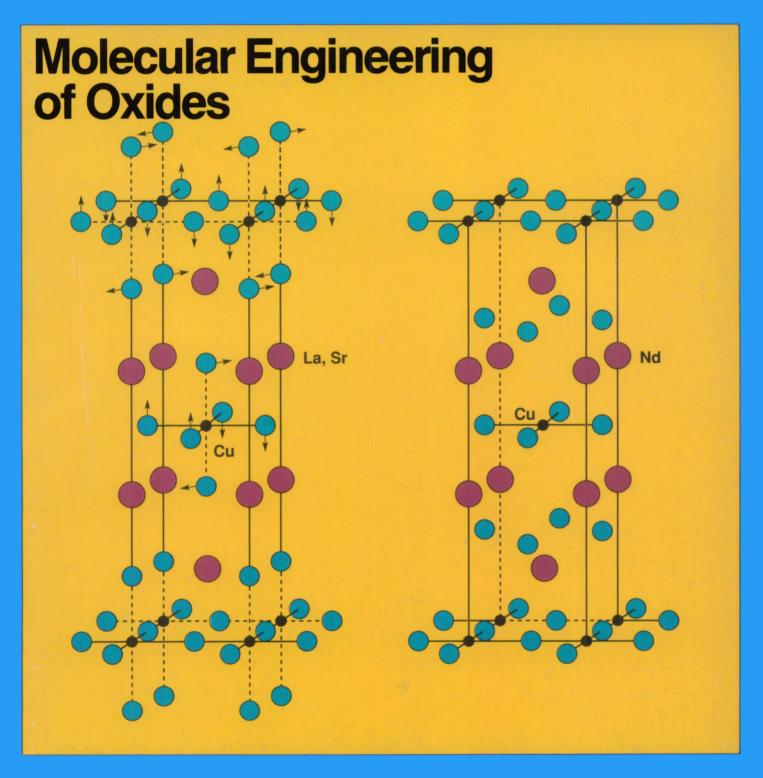
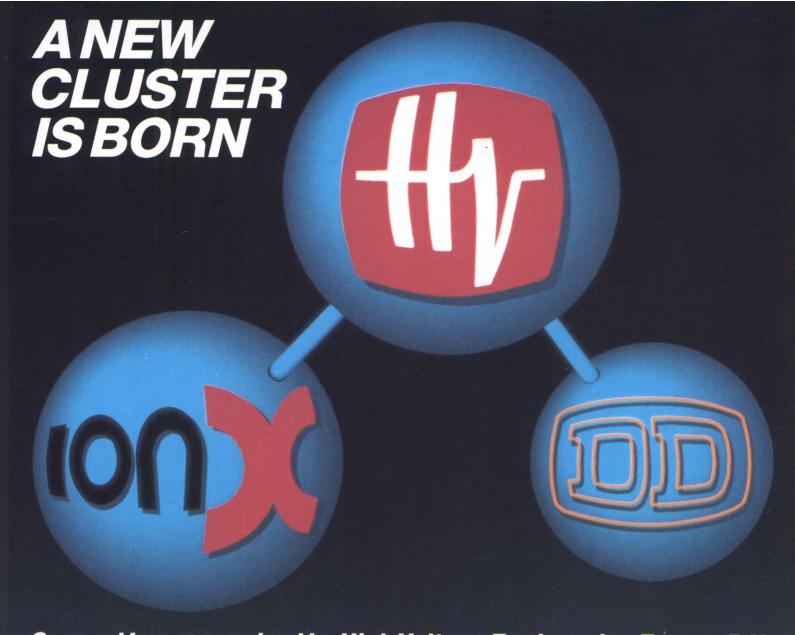
MRS BULLETIN

May 1990

Volume XV, Number 5

Serving the International Materials Research Community





General Ionex acquired by High Voltage Engineering Europa B.V.

In December 1987 High Voltage Engineering Europa B.V. (HVEE) acquired Dowlish Developments Ltd (DD), an accelerator tube manufacturer located in the United Kingdom.

On April 10, 1989, HVEE purchased the General Ionex Analytical Product Group from Genus Inc. based in the United States.

Through this acquisition HVEE positions itself as the largest and most diverse manufacturer of particle accelerators for the scientific and industrial research communities.

The acquired General Ionex (GI) product lines, which include the Tandetron accelerator systems and Model 4175 RBS Analyser, will be manufactured in HVEE's new, well-equipped facility in Amersfoort, The Netherlands.

World wide marketing of all products from HVEE, DD and GI will originate from HVEE Amersfoort with sales and service offices in the USA, Europe and Japan.

After addition of the newly acquired products HVEE's product lines include:

- Ion Accelerator Systems
 - Air insulated accelerators up to 500 kV
 - Single ended Van de Graaff accelerators up to 4 MV
 - Tandem Tandetron accelerators up to 3 MV/TV
- Research ion implanters
- Beam energies 10 keV-9 MeV and higher
- Systems for ion beam analysis
 - Systems for RBS, PIXE, PIGE, NRA, ERD, MACS and MEIS
- Components
 - HV power supplies, electron and ion accelerator tubes, ion sources beamline components, beam monitoring equipment, UHV sample manipulators, etc.

For further information on this transaction and product literature please contact HVEE in Amersfoort/NL.



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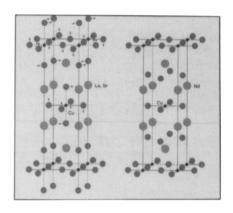
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ON THE COVER: A figure from Prof. John B. Goodenough's Von Hippel Address given at the 1989 MRS Fall Meeting in Boston. Prof. Goodenough discussed ''four fundamental problems relevant to high T_c superconductivity in the copper oxides.'' In speaking about intergrowth structures he used this figure to depict the T/O and T' tetragonal structures of La_cCuO_a . The arrows in the left structure indicate cooperative oxygen-atom displacements in orthorhombic (O) phase T < T_c . The text of Prof. Goodenough's Von Hippel Address begins on p. 23.

Editor's Note: The technical feature on angular distribution Auger microscopy by D.G. Frank et al. references an earlier publication on the same general topic by the same authors, which appeared in the January 12, 1990 issue of Science (Vol. 247, p. 182-188). The Science article has sparked significant reaction in the form of letters challenging the fundamental physical basis upon which data were interpreted. We expect Science to publish both the criticism and a rebuttal from the authors in May. Readers are encouraged to review the data and draw their own conclusions.

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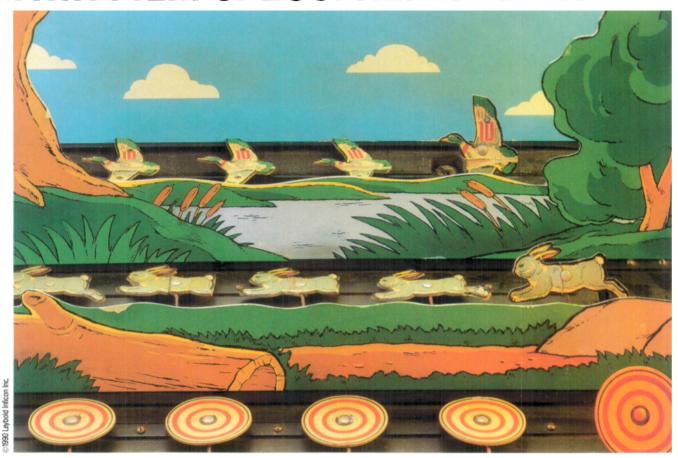
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